

54ACTQ574

Quiet Series Octal D Flip-Flop with TRI-STATE® Outputs

General Description

The ACTQ574 is a high-speed, low-power octal D-type flip-flop with a buffered Common Clock (CP) and a buffered common Output Enable (\overline{OE}). The information presented to the D inputs is stored in the flip-flops on the LOW-to-HIGH clock (CP) transition.

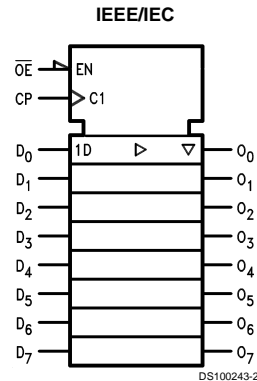
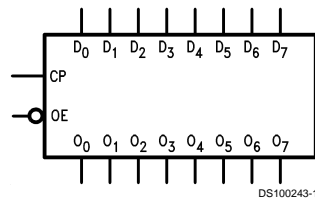
ACTQ574 utilizes Quiet Series technology to guarantee quiet output switching and improve dynamic threshold performance. FACT Quiet Series™ features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

The ACTQ574 is functionally identical to the 'ACTQ374 but with different pin-out.

Features

- I_{CC} and I_{OZ} reduced by 50%
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Inputs and outputs on opposite sides of the package allowing easy interface with microprocessors
- Functionally identical to the ACTQ374
- TRI-STATE outputs drive bus lines or buffer memory address registers
- Outputs source/sink 24 mA
- Faster prop delays than the standard ACT574
- 4 kV minimum ESD immunity

Logic Diagrams

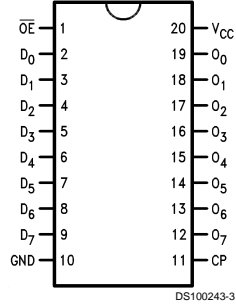


Pin Names	Description
D ₀ -D ₇	Data Inputs
CP	Clock Pulse Input
\overline{OE}	TRI-STATE Output Enable Input
O ₀ -O ₇	TRI-STATE Outputs

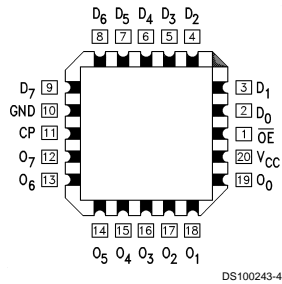
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Connection Diagrams

Pin Assignment for DIP and Flatpak



Pin Assignment for LCC



Functional Description

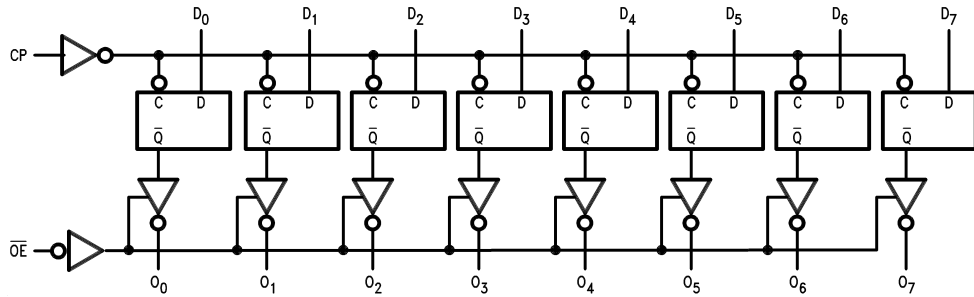
The ACTQ574 consists of eight edge-triggered flip-flops with individual D-type inputs and TRI-STATE true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D inputs that meet the setup and hold time requirements on the LOW-to-HIGH Clock (CP) transition. With the Output Enable (\overline{OE}) LOW, the contents of the eight flip-flops are available at the outputs. When \overline{OE} is HIGH, the outputs go to the high impedance state. Operation of the \overline{OE} input does not affect the state of the flip-flops.

Function Table

Inputs		Internal	Outputs		Function
\overline{OE}	CP	D	Q	O_N	
H	H	L	NC	Z	Hold
H	H	H	NC	Z	Hold
H	\nearrow	L	L	Z	Load
H	\nearrow	H	H	Z	Load
L	\nearrow	L	L	L	Data Available
L	\nearrow	H	H	H	Data Available
L	H	L	NC	NC	No Change in Data
L	H	H	NC	NC	No Change in Data

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Immaterial
 Z = High Impedance
 \nearrow = LOW-to-HIGH Transition
 NC = No Change

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	-0.5V to +7.0V
DC Input Diode Current (I_{IK})	
$V_I = -0.5V$	-20 mA
$V_I = V_{CC} + 0.5V$	+20 mA
DC Input Voltage (V_I)	-0.5V to $V_{CC} + 0.5V$
DC Output Diode Current (I_{OK})	
$V_O = -0.5V$	-20 mA
$V_O = V_{CC} + 0.5V$	+20 mA
DC Output Voltage (V_O)	-0.5V to $V_{CC} + 0.5V$
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	±50 mA
Storage Temperature (T_{STG})	-65°C to +150°C
DC Latch-Up Source or Sink Current	±300 mA
Junction Temperature (T_J)	

CDIP

175°C

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'ACTQ	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	
54ACTQ	-55°C to +125°C
Minimum Input Edge Rate $\Delta V/\Delta t$	
'ACTQ Devices	
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 4.5V, 5.5V	125 mV/ns

Note 1: All commercial packaging is not recommended for applications requiring greater than 2000 temperature cycles from -40°C to +125°C.

Note 2: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

DC Electrical Characteristics for 'ACTQ Family Devices

Symbol	Parameter	V_{CC} (V)	54ACTQ	Units	Conditions
			$T_A =$ -55°C to +125°C Guaranteed Limits		
V_{IH}	Minimum High Level Input Voltage	4.5	2.0	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
		5.5	2.0		
V_{IL}	Maximum Low Level Input Voltage	4.5	0.8	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
		5.5	0.8		
V_{OH}	Minimum High Level Output Voltage	4.5	4.4	V	$I_{OUT} = -50 \mu A$
		5.5	5.4		
		4.5	3.70	V	(Note 3) $V_{IN} = V_{IL}$ or V_{IH} $I_{OH} = -24 mA$ $I_{OH} = -24 mA$
		5.5	4.70		
V_{OL}	Maximum Low Level Output Voltage	4.5	0.1	V	$I_{OUT} = 50 \mu A$
		5.5	0.1		
		4.5	0.50	V	(Note 3) $V_{IN} = V_{IL}$ or V_{IH} $I_{OL} = 24 mA$ $I_{OL} = 24 mA$
		5.5	0.50		
I_{IN}	Maximum Input Leakage Current	5.5	±1.0	μA	$V_I = V_{CC}, GND$
I_{OZ}	Maximum TRI-STATE Leakage Current	5.5	±5.0	μA	$V_I = V_{IL}, V_{IH}$ $V_O = V_{CC}, GND$
I_{CCT}	Maximum $I_{CC}/Input$	5.5	1.6	mA	$V_I = V_{CC} - 2.1V$
I_{OLD}	(Note 4) Minimum Dynamic	5.5	50	mA	$V_{OLD} = 1.65V Max$
I_{OHD}	Output Current	5.5	-50	mA	$V_{OHD} = 3.85V Min$
I_{CC}	Maximum Quiescent Supply Current	5.5	80.0	μA	$V_{IN} = V_{CC}$ or GND (Note 5)

DC Electrical Characteristics for 'ACTQ Family Devices (Continued)

Symbol	Parameter	V _{CC} (V)	54ACTQ		Units	Conditions
			T _A = -55°C to +125°C			
			Guaranteed Limits			
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	5.0	1.5		V	(Notes 6, 7)
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	5.0	-1.2		V	(Notes 6, 7)

Note 3: All outputs loaded; thresholds on input associated with output under test.

Note 4: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5: I_{CC} for 54ACTQ @ 25°C is identical to 74ACTQ @ 25°C.

Note 6: Plastic DIP package.

Note 7: Max number of outputs defined as (n). Data inputs are driven 0V to 3V. One output @ GND.

Note 8: Max number of data inputs (n) switching. (n-1) inputs switching 0V to 3V ('ACTQ). Input-under-test switching: 3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), f = 1 MHz.

AC Electrical Characteristics

Symbol	Parameter	V _{CC} (V) (Note 9)	54ACTQ		Units
			T _A = -55°C to +125°C C _L = 50 pF		
			Min	Max	
f _{max}	Maximum Clock Frequency	5.0	95		MHz
t _{PLH} , t _{PHL}	Propagation Delay CP to O _n	5.0	1.0	11.0	ns
t _{PZH} , t _{PZL}	Output Enable Time	5.0	1.0	11.0	ns
t _{PHZ} , t _{PLZ}	Output Disable Time	5.0	1.0	10.0	ns

Note 9: Voltage Range 5.0 is 5.0V ±0.5V.

Note 10: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t_{OSHL}) or LOW to HIGH (t_{OSLH}). Parameter guaranteed by design.

AC Operating Requirements

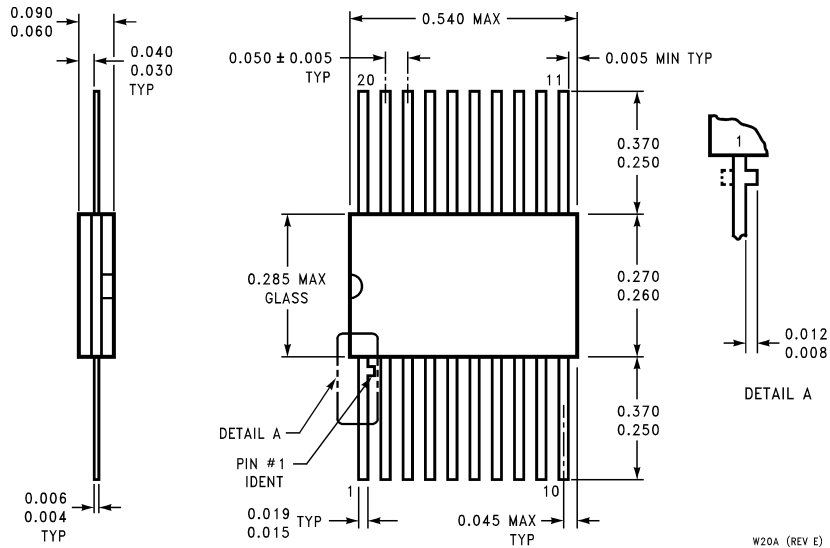
Symbol	Parameter	V _{CC} (V) (Note 11)	54ACTQ		Units
			T _A = -55°C to +125°C C _L = 50 pF		
			Guaranteed Minimum		
t _S	Setup Time, HIGH or LOW D _n to CP	5.0	3.5		ns
t _H	Hold Time, HIGH or LOW D _n to CP	5.0	2.0		ns
t _W	CP Pulse Width, HIGH or LOW	5.0	5.0		ns

Note 11: Voltage Range 5.0 is 5.0V ±0.5V

Capacitance

Symbol	Parameter	Typ	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = OPEN
C _{PD}	Power Dissipation Capacitance	40.0	pF	V _{CC} = 5.0V

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



**20-Lead Ceramic Flatpak (F)
NS Package Number W20A**

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